


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/689,480	ANJANAPPA ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Dinh Q. Nguyen	3752	

SEARCHED			
Class	Subclass	Date	Examiner
239	102.1		
	585.1-		
	585.5		
	533.2		
	583		
	584	11/30/05	✓D
251	129.15		
	129.21		
	129.06	11/30/05	✓D
137	82	11/30/05	✓D

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR